

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10645164	TRUNZ ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	Chon, Peter	2112

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
257	724,680,684,783,83,88	12/22/2006	PC
174	52.1,52.2,52.3	12/22/2006	PC
250	227,220,239	12/22/2006	PC

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
East	12/22/2006	PC

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>